

Notice of References Cited	Application/Control No. 10/003,068	Applicant(s)/Patent Under Reexamination KYE, HWAN WON	
	Examiner Hong Cho	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0049861 A1	04-2002	Bunn et al.	709/247
*	B	US-2002/0062394 A1	05-2002	Bunn et al.	709/246
*	C	US-2002/0062380 A1	05-2002	MOHAMMED et al.	709/228
*	D	US-2002/0080868 A1	06-2002	Bunn et al.	375/222
*	E	US-2002/0073227 A1	06-2002	Bunn et al.	709/236
*	F	US-6,438,123 B1	08-2002	Chapman, John T.	370/351
*	G	US-2002/0106029 A1	08-2002	Bunn et al.	375/257
*	H	US-6,650,624 B1	11-2003	Quigley et al.	370/252
*	I	US-6,788,707 B1	09-2004	Horton et al.	370/474
*	J	US-6,901,049 B1	05-2005	Chapman, John T.	370/230
*	K	US-6,909,715 B1	06-2005	Denney et al.	370/392
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.